

Search Notes

Application/Control No.

10/706,626

Examiner

Matthew G. Kayrish

Applicant(s)/Patent under
Reexamination

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Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
360	235.6	5/11/2006	MK
360	235.8	5/11/2006	MK
360	235.9	5/11/2006	MK
360	236	5/11/2006	MK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB, DERWENT) (See Attached Search History)	5/11/2006	MK